



# Lesson learnt from the Isograph Training Course

Winterthur 24<sup>th</sup> to 26<sup>th</sup> of July 2017

Miriam Blumenschein, Saskia Hurst and Estrella Vergara

- RAS Working Group Meeting -

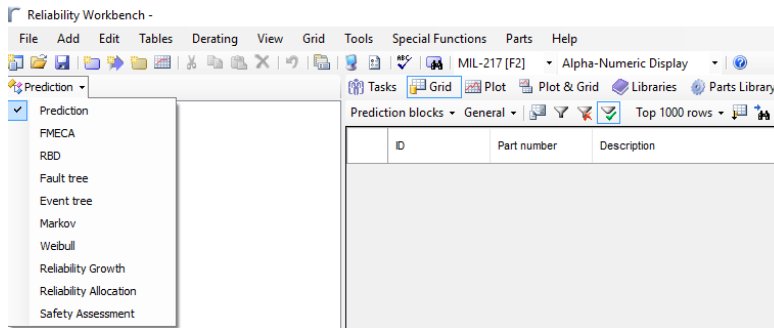
31<sup>st</sup> of August 2017

# 1. Isograph for beginners

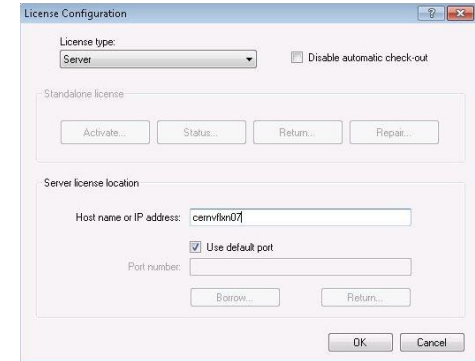
Estrella Vergara

# Reliability Workbench

Available in CMF Packages: *Isograph – RelWorkbench 13.01*



During installation...

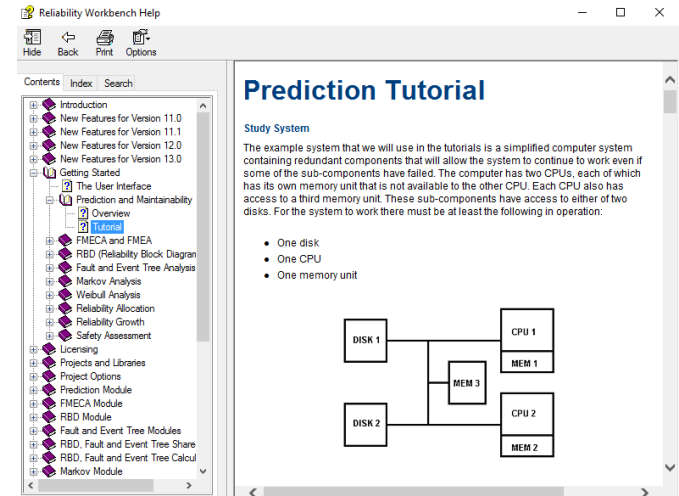


Password needed for installation: *cernvflxn07*

## Modules available

CERN licenses

- Prediction Methods
- Failure Mode Effect and Criticality Analysis (FMECA)
- Reliability Block Diagrams (RBD)
- Fault Tree Analysis (FTA)
- Event Tree Analysis (ETA)
- Markov Analysis
- Weibull
- Reliability Growth
- Reliability Allocation



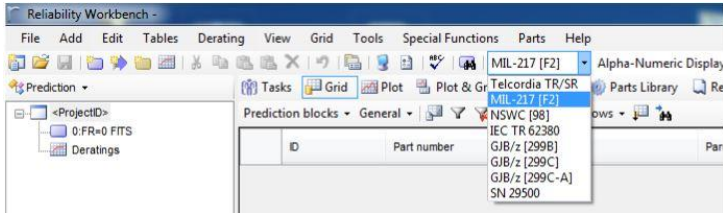
Tutorials for each module:

*Help → Getting Started → Tutorial*



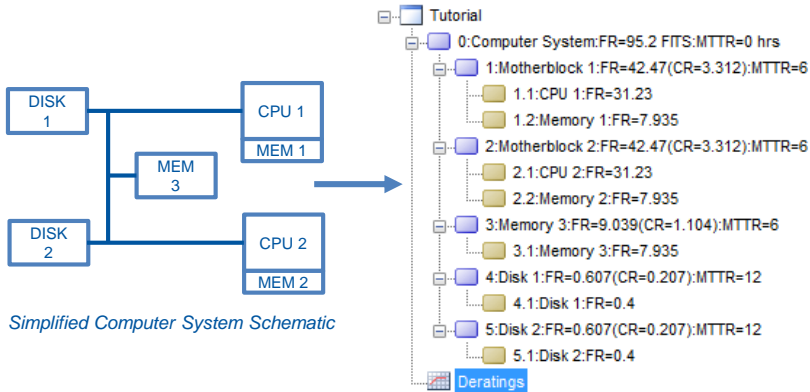
# Prediction module

Provide consistent methods of estimating **failure rates** using **Handbooks and standards**

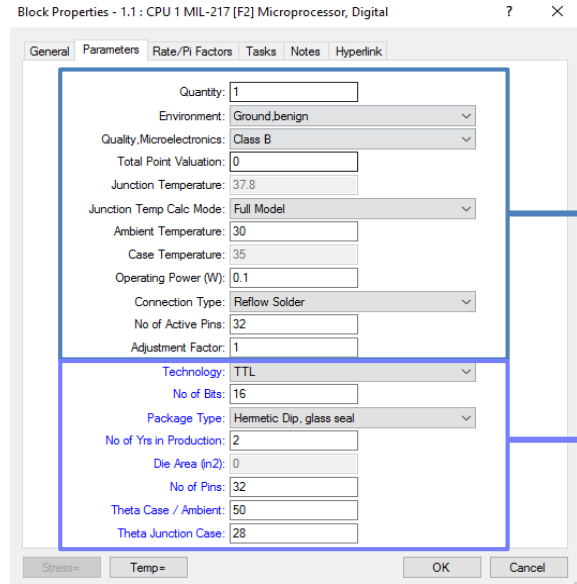


- |   |  |
|---|--|
| <b>CERN license:</b> <ul style="list-style-type: none"> <li>• Telcordia TR/SR</li> <li>• MIL-217 Prediction</li> <li>• NSWC Prediction</li> </ul> | <b>Only 1 license:</b> <ul style="list-style-type: none"> <li>• 217 Plus Prediction</li> <li>• FIDES Prediction</li> </ul> |
|---|--|

## Project Hierarchy Diagram



## Block Systems and Components Properties



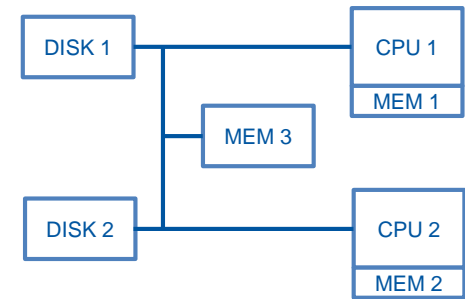
Environmental Properties

Parameters for the component type (defined by Handbook or Standard)  
- External Category: entering data manually

- Entering prediction data manually or using **libraries** (Project and Library must follow the same Standard or Handbook)
- Possibility to associate **maintenance** tasks in the prediction hierarchy
- Option to specify the **phases** if the ambient conditions change during the lifetime of the system

# Prediction module

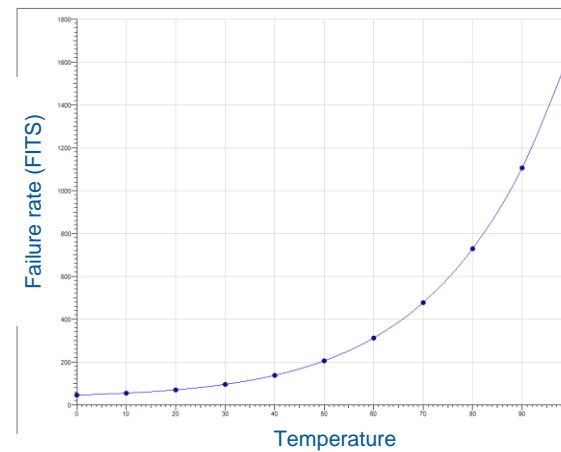
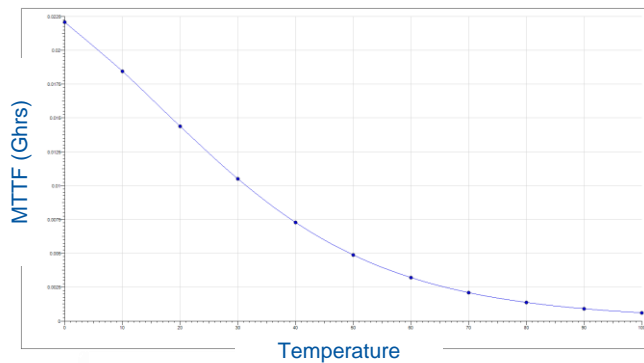
## Results



*Simplified Computer System Schematic*

ID	Part number	Description	Parent	Category	Sub category	Failure rate	MTTF	MTRR
1	0-1	Motherblock 1		System Block		42.47	0.02354	6
1.1	0-1-1	CPU 1	1	Microprocessor, ...	TTL	31.23	0.03202	0
1.2	0-1-2	Memory 1	1	Micro, Not EEPROM	ROM	7.935	0.126	0
2	0-2	Motherblock 2		System Block		42.47	0.02354	6
2.1	0-1-1	CPU 2	2	Microprocessor, ...	TTL	31.23	0.03202	0
2.2	0-1-2	Memory 2	2	Micro, Not EEPROM	ROM	7.935	0.126	0
3	0-3	Memory 3		System Block		9.039	0.1106	6
3.1	0-1-2	Memory 3	3	Micro, Not EEPROM	ROM	7.935	0.126	0
4	0-4	Disk 1		System Block		0.607	1.647	12
4.1	0-4-1	Disk 1	4	External		0.4	2.5	0
5	0-5	Disk 2		System Block		0.607	1.647	12
5.1	0-5-1	Disk 2	5	External		0.4	2.5	0










## Plots








# Fault Tree Analysis (FTA)

- Show interaction to failures
- Creation of fault trees manually

## GATES TYPES

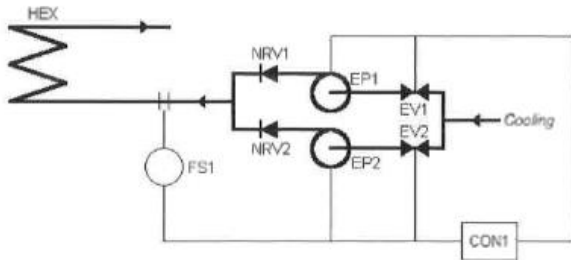
Symbol	Name	Meaning	Inputs
	OR	TRUE if any input is TRUE	$\geq 2$
	AND	TRUE if all inputs are TRUE	$\geq 2$
	VOTE	TRUE if $m$ inputs are TRUE	$\geq 3$
	EXCLUSIVE OR	TRUE if one and only one inputs is TRUE	2
	INHIBIT GATE	TRUE if all inputs are TRUE; one input is conditional	$\geq 2$
	PRIORITY AND	TRUE if inputs occur in left to right order	$\geq 2$
	NOT	TRUE if inputs is FALSE	1
	Transfer In	Inputs appear elsewhere on same page or on another page	
	Transfer Out	Output appears elsewhere on same page or another page	

## EVENT TYPES

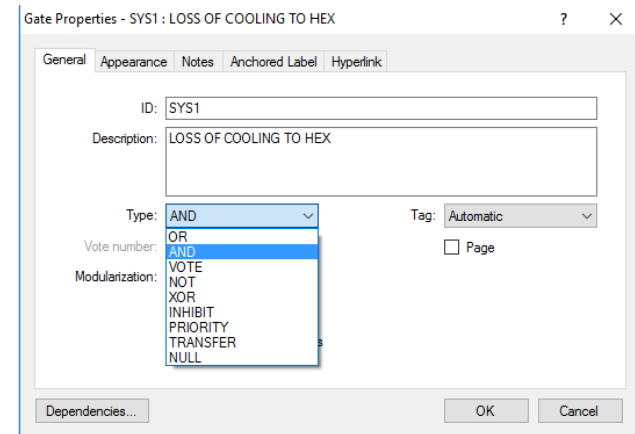
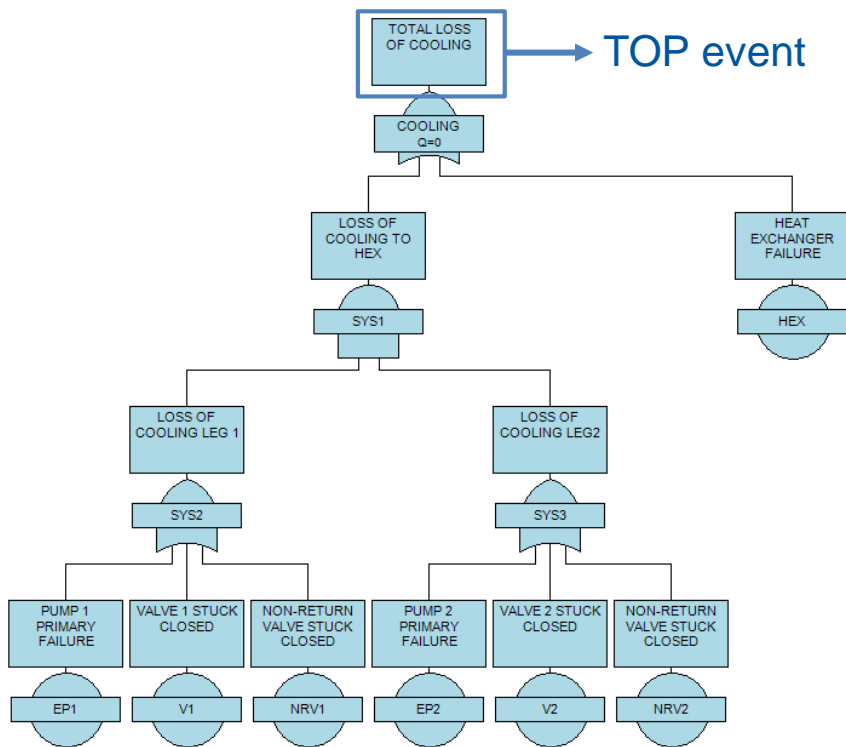
Symbol	Name	Meaning
	BASIC	Basic event
	UNDEVELOPED	A system event which is yet to be developed
	CONDITIONAL	Conditional event connected to an inhibit gate
	HOUSE	Definitely operating or definitely not operating
	DORMANT	Failure not immediately revealed; latent/ hidden failure

# Fault Tree Analysis (FTA)

- Show interaction to failures
- Creation of fault trees manually through gates



Simple Cooling System

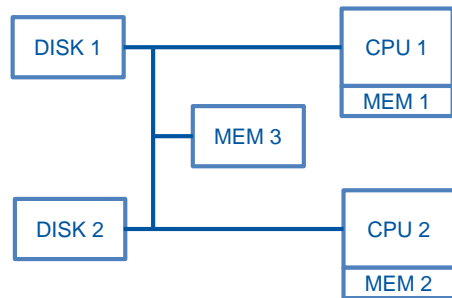


- No limit of gates or events (“Page” checkbox)
- Special Function: Multiple Project option:
  - ID must be coherent
  - Connection between gates (no events)
- **Minimal Cut Set:**
  - Minimum combination of events which cause TOP event
  - First step of Analysis
  - Produced using Boolean algebra

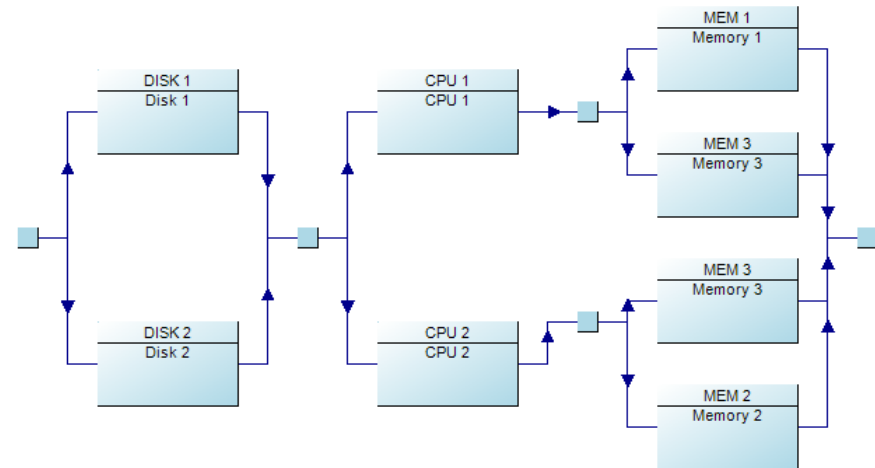


# Reliability Block Diagram (RBD)

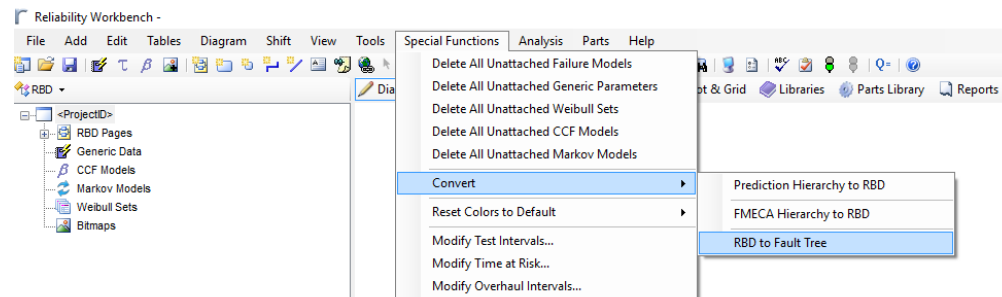
- Used to predict the **reliability** of entire systems
- Similar to FTA:
  - RBD → Process (availability) / FTA → Hazards



*Simplified Computer System Schematic*



- Flow from left to right – easy to read
- Blocks connected in series/ parallel
- Option to Copy-Paste to duplicate a block (e.g. “MEM 3”)
- Special functions: RBD to FTA, Prediction to RBD and FMECA to RBD



31/08/2017

# Reliability Block Diagram (RBD)

## ASSIGNING FAILURE MODELS TO BLOCKS

- Failure and repair date is entered in a failure model
  - Local Failure Model: attached to one block only
  - Generic Failure Model: can be attached to multiple blocks
- Applicable for FTA as well

The screenshot displays the Reliability Workbench interface. On the left, a tree view under 'RBD Pages' shows 'Generic Data' containing 'DISK UNIT', 'CPU', 'MEM', and 'MEM3'. A blue arrow points from this tree to the text 'Generic Failure Models'. The main workspace shows an RBD diagram with blocks: DISK 1 (FR=0.4), DISK 2 (FR=0.4), CPU 1 (FR=0.3123), CPU 2 (FR=0.3123), MEM 1 (Memory 1, FR=0.7808), MEM 3 (Memory 3, FR=1.092), and MEM 2 (Memory 2, FR=...). A 'Block Properties' dialog box for 'MEM 2: Memory 2' is open, showing fields for ID (MEM 2), Description (Memory 2), Logic mode (Probabilistic), Failure model (MEM (Generic)), and CCF model (Not set). A blue arrow points from the text 'Assigning Generic Failure Model to a Block' to the 'Failure model' field in the dialog box. The CERN logo is in the bottom left corner.

# Reliability Block Diagram (RBD)

## PERFORMING AN ANALYSIS - Results

### Summary

Results for block SY1

Summary
  Importance
  Cut sets
  Appearance

Parameter	Point Value
Unavailability	2.861E-12
Frequency	1.717E-06
CFI	1.717E-06
Number expected fail...	1.717E-06
Unreliability	1.717E-06
MTTF	Not calculated
MTTR	Not calculated
Total down time	2.861E-12
Mean unavailability	2.861E-12
Risk reduction factor	3.495E+11
Q/T	2.861E-12
Used method	Cross product
Number of compact s...	5

**Cut Sets:** Combination of component block failures that will cause system failure

Summary
  Importance
  Cut sets
  Appearance

No.	Q	Minimal cut set
1	1.778E-12	DISK 1.DISK 2
2	1.084E-12	CPU 1.CPU 2
3	9.862E-18	CPU 1.MEM 3.MEM 2
4	2.466E-17	MEM 1.MEM 3.MEM 2
5	9.862E-18	MEM 1.CPU 2.MEM 3

**Importance:** Block's contribution to the unavailability of the system

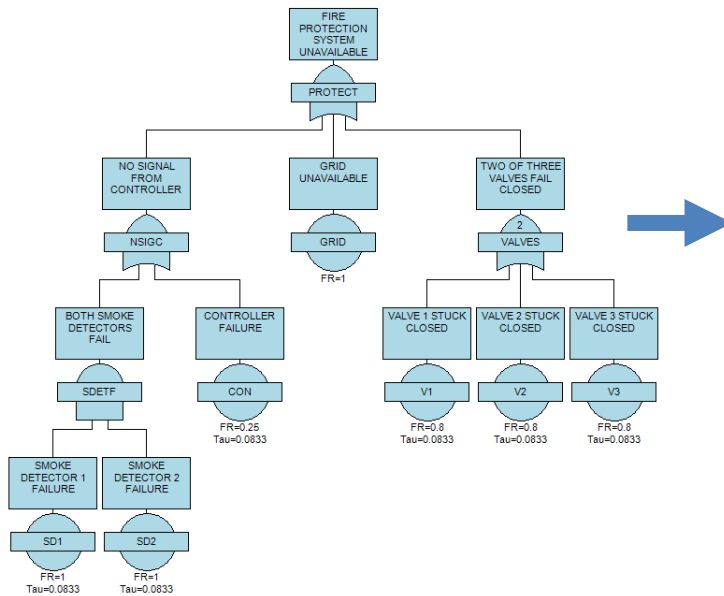
Summary
  Importance
  Cut sets
  Appearance

Event ID	Fussell-Vesely	Bimbaum	Barlow-Proschan	Sequential	Risk Reduction Worth	Risk Achievement ...
DISK 2	0.6213	1.333E-06	0.3106	0.3106	2.64	4.66E+05
DISK 1	0.6213	1.333E-06	0.3106	0.3106	2.64	4.66E+05
CPU 1	0.3787	1.041E-06	0.1894	0.1894	1.61	3.638E+05
CPU 2	0.3787	1.041E-06	0.1894	0.1894	1.61	3.638E+05
MEM 3	1.551E-05	1.219E-11	7.755E-06	1.551E-05	1	5.261
MEM 2	1.206E-05	1.326E-11	6.032E-06	1.206E-05	1	5.635
MEM 1	1.206E-05	1.326E-11	6.032E-06	1.206E-05	1	5.635

# Event Tree Analysis (ETA)

- Identifies outcomes of initiating event
- ETA & FTA closely linked:
  - FTA can be used to quantify events in ETA sequence
  - Use cut sets and same quantitative methodology

Fault Tree created in FTA module



Event Tree Analysis

FIRE	PRIMARY FIRE PROTECTION SYSTEM	SECONDARY FIRE PROTECTION	Consequence	Frequency
w=0.2	G=0.01762	G=0.06437		0.2
		Success	NO FATALITIES	0.1838
		Failure	1 FATALITY	0.01265
Failure		Success	2 TO 8 FATALITIES	0.003335
		Failure	GREATER THAN 8 FATALITIES	0.0002294

# Failure Mode Effect and Criticality Analysis (FMECA)

- Rates failure modes by danger

Date: 05/07/2017		FMEA CIBDS: Failure chain all levels					Page 1 of 38	
Id	Component	Component FM	Effect immediate	Effects +1	Effects +2	Effects +3	Effects on LBDS	
1.1.1.1	P1	not considered	Not considered					
1.1.1.2	P2	not considered	Not considered					
1.1.1.3	IC26	Input open	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor	1.1.3 Incorrect monitoring information	1.16 Incorrect monitoring information	7 Incorrect monitoring information CIBDS	Incorrect monitoring information CIBDS	
		Output open	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor	1.1.3 Incorrect monitoring information	1.16 Incorrect monitoring information	7 Incorrect monitoring information CIBDS	Incorrect monitoring information CIBDS	
		Supply open	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor	1.1.3 Incorrect monitoring information	1.16 Incorrect monitoring information	7 Incorrect monitoring information CIBDS	Incorrect monitoring information CIBDS	
		Output stuck low	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor	1.1.3 Incorrect monitoring information	1.16 Incorrect monitoring information	7 Incorrect monitoring information CIBDS	Incorrect monitoring information CIBDS	
		Output stuck high	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor	1.1.3 Incorrect monitoring information	1.16 Incorrect monitoring information	7 Incorrect monitoring information CIBDS	Incorrect monitoring information CIBDS	
1.1.1.4	IC22	Input open	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor + No transfer of CIBDS rearm controlling data from MenA20 processor to Monitoring_FPGA	1.1.3 Incorrect monitoring information 1.1.11 Remote + BIS freq: no effect 1.1.21 Remote + no Bis freq: no effect 1.1.42 Remote + Transition to BIS freq: arming is blocked 1.1.51 Local + no BIS freq: no effect 1.1.31 Remote + Transition to no BIS freq: no effect	1.16 Incorrect monitoring information 1.17 No effect 1.13 Arming procedure blocked	7 Incorrect monitoring information CIBDS 8 No effect 10 Arming procedure blocked	Incorrect monitoring information CIBDS No effect Arming procedure blocked	
		Output open	Incorrect transfer of CIBDS monitoring data from Monitoring_FPGA to MenA20 processor + No transfer of CIBDS rearm controlling data from MenA20 processor to Monitoring_FPGA	1.1.3 Incorrect monitoring information 1.1.11 Remote + BIS freq: no effect 1.1.21 Remote + no Bis freq: no effect 1.1.42 Remote + Transition to BIS freq: arming is blocked 1.1.51 Local + no BIS freq: no effect 1.1.31 Remote + Transition to no BIS freq: no effect	1.16 Incorrect monitoring information 1.17 No effect 1.13 Arming procedure blocked	7 Incorrect monitoring information CIBDS 8 No effect 10 Arming procedure blocked	Incorrect monitoring information CIBDS No effect Arming procedure blocked	

## 2. Compendium of useful features

Miriam Blumenschein

Prediction – FMECA – Fault Tree

# Prediction

## 1. Component library

- Construct a project from a library:
  - *File ► Attach Library*
  - Drag and drop parts or structures to system structure
  - No automatic update if library is modified
- Build a library: create components in prediction (blue fields)
- Common CERN library?

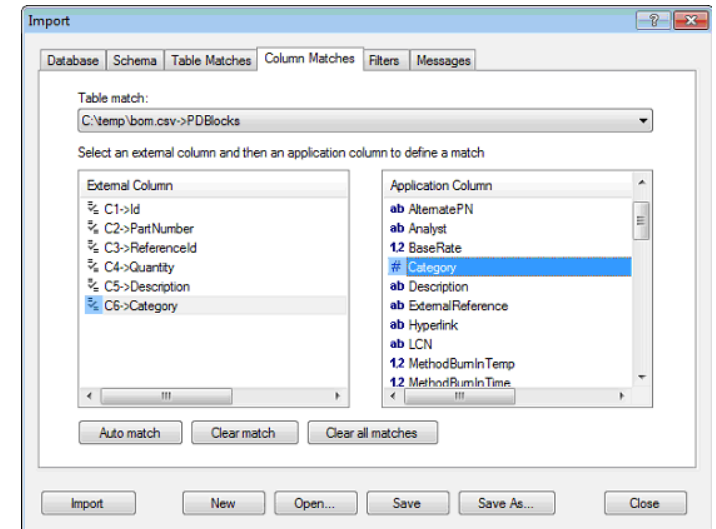
The screenshot displays the Prediction software interface. The top menu bar includes 'Tasks', 'Grid', 'Plot', 'Plot & Grid', 'Libraries' (highlighted with a red box), 'Parts Library', and 'Reports'. The left pane shows a project tree for '<ProjectID>' with a root component '0:FR=1.288E+04 FITS' and a sub-component '1:OPL-Repeater\_HW02:0-1:FR=5935(CR=5.658)'. This sub-component contains 11 sub-components, including capacitors (1.1-1.7), an AFBR (1.4), a ZENER-DIODE (1.9), and two 74LVC1G125DBV components (1.10-1.11). The right pane shows a project tree for '<ProjectID> - \\cern.ch\dfs\Users\m\mblumens\Desktop\CERN parts library.rwb'. The root component is '0', which contains sub-components '1:Capacitors: System Block' (with sub-components 1.1 and 1.2), '2:Coils: System Block' (with sub-component 2.1), '3:Diode: System Block', '4: Integrated Circuit: System Block', '5: Transistor: System Block', and '8: Resistor: System Block'. There are also 'Tasks' and 'Deratings' icons at the bottom of the right pane.

# Prediction

## 2. Import of bill of material:

- Easy to import: blue fields (component properties) part number, ID, quantity, description and category
- ► *Manual chapter “Importing a Bill of Materials”*
- Not (yet) easy to import: black fields (operating environment), filled in manually
- **Common Excel format of BOM ?**

Id	PartNumber	Quantity	Description	Category
1	0-1	1	OPL-Repeater_HW02	MIL-BK
2	0-2	1	OPL-Trans_1414_HW02	MIL-BK
3	0-3	1	OPL-REC-2418_HW02	MIL-BK
1.1	C-EUC0805_1000nF	1		MIL-CR
1.2	C-EUC0805_100nF	1		MIL-CR
1.3	C-EUC0805_100nF	1		MIL-CR
1.4	AFBR-2418	1		MIL-LB
1.5	C-EUC0805_100nF	1		MIL-CR

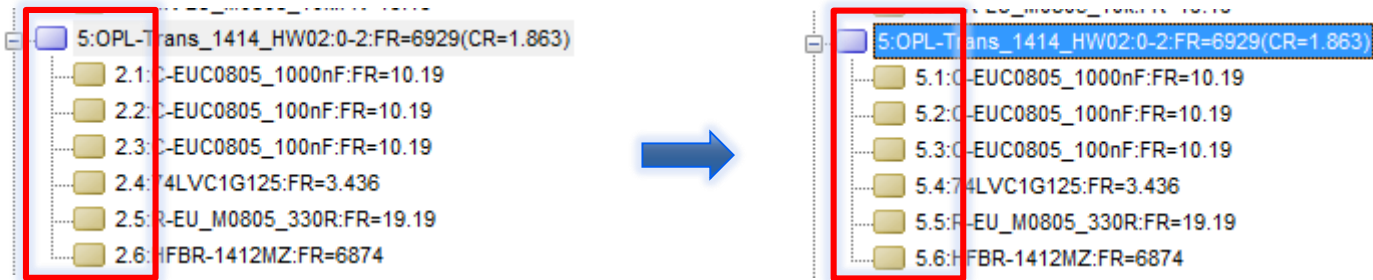




# Prediction

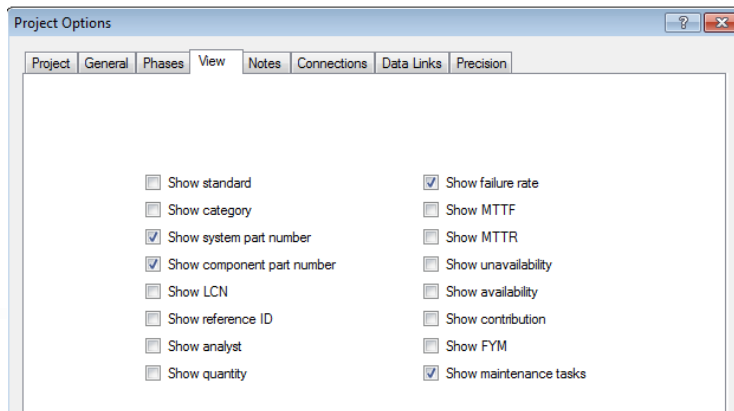
## 3. Rename option

- Objects under the current tree control selection will be renamed based on the name of their parent
- *Select parent block ► Tools ► Rename ► Blocks under selection*



## 4. View option:

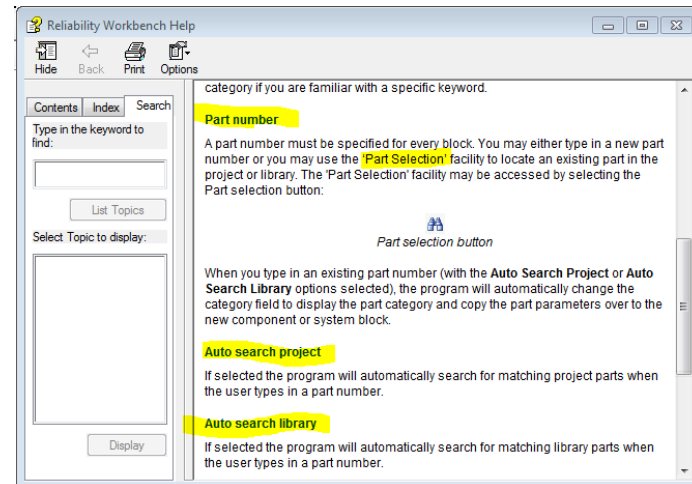
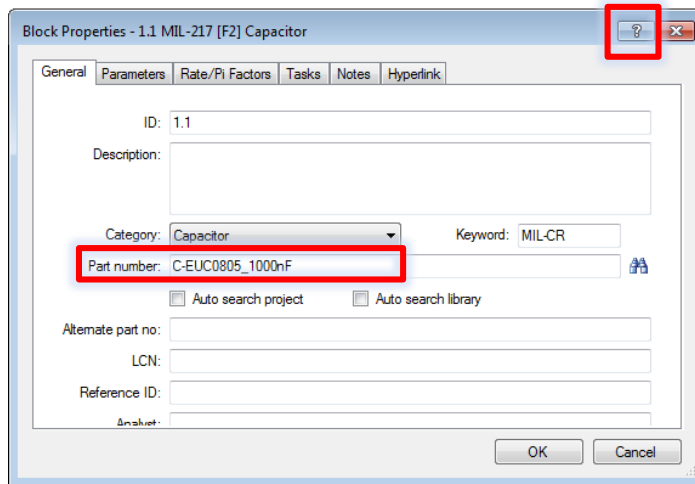
- Determination of the data which is displayed in the project tree control
- *Project Options ► View ► check “Show category”; “Show component part; ... number”*



# Prediction

## 5. Help option in dialog boxes

- “?” on the top right in each dialog opens corresponding chapter of the manual



## 6. Part number

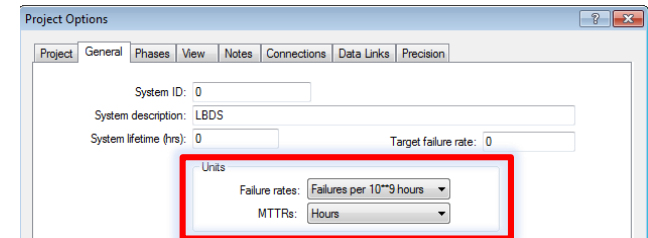
Several Functions are linked to the part number

- Blue fields = component properties: same properties for same part number
- Black fields = operating environment: independent of part number
- Part Selection facility, Auto search project, auto search library, Auto Add Apportioned Failure Modes, Linked block, ...

# Prediction

## 7. Unit of failure rate

- *Project Options ► General ► Units*

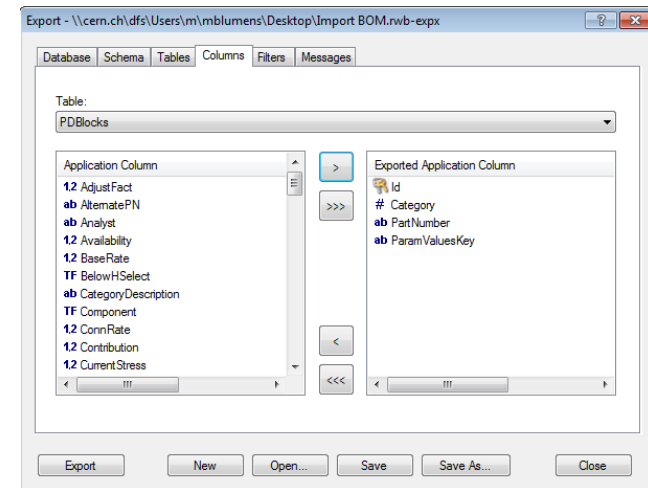


## 8. Change component parameters

- Temperature, Environment, ...
- *Select section in tree control ► Special Functions ► change temperature/ MIL-217 environment*

OR

- Export block properties to Excel (table PDBlocks; columns PartNumber, ParamValuesKey), find and replace properties in Excel, import Excel file



## 9. Project Options, Special Functions and Tools change from one module to the other, always worth having a look at

## 10. Recommendation: Always create system structure in the prediction module, even if no prediction is performed

# From one module to another

## 1. Data conversion

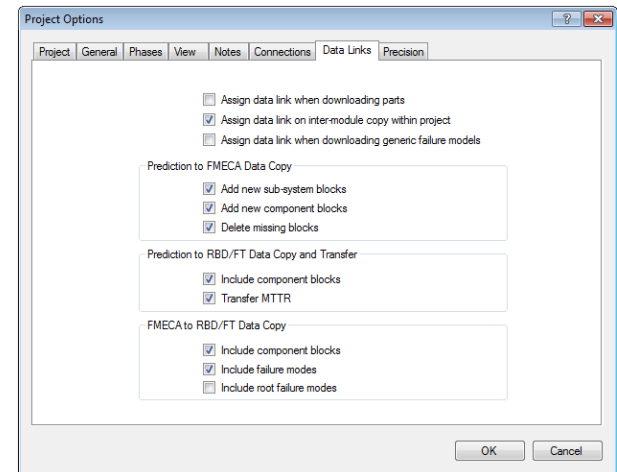
- prediction hierarchy to FMECA, RBD, fault tree
- FMECA hierarchy to RBD, fault tree
- RBD to fault tree
- Common way: Prediction to FMECA to Fault Tree
- *Special Functions* ► *Convert pull-down menu*

## 2. Data links

- Needs to be defined before the data conversion!
- Data links will be automatically created between objects when copying between modules
- Customize data conversion: *Project options* ► *Data links* ► *check “Assign data link on inter-module copy within project”*
- Prediction to FMECA: Edit ► *Transfer linked data* ► *run the FMECA simulation*
- *FMECA to Fault Tree: Run the FMECA simulation* Edit ► *Transfer linked data* ► *run the Fault Tree simulation*

## 3. Update of system structure

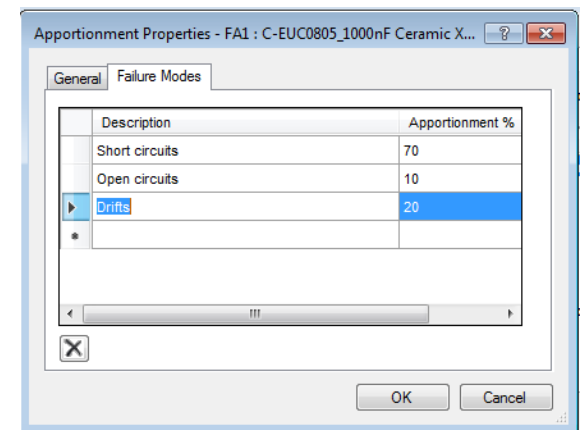
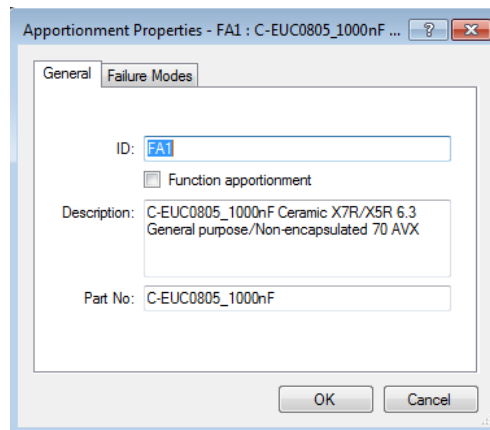
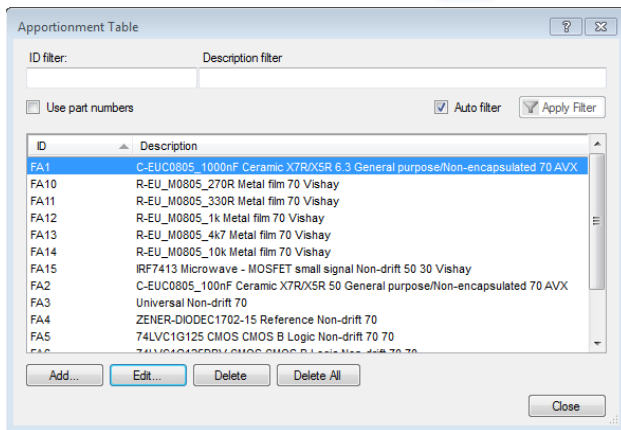
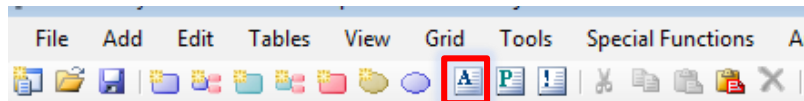
- Failure modes remain
- Prediction to FMECA: *Special Functions* ► *Convert pull-down menu*



# FMECA-module

## 1. Apportionment table

- Lists a component type (defined by the part number) and its failure modes and % Apportionment table can be imported from excel
- Add failure modes to existing blocks: Add ► Auto Add Apportioned Failure Modes
- OR
- Add apportioned block
- Common CERN apportionment table?



# FMECA-module

## 2. Severity matrix

- Tabulates the number of failure mode contributors in each severity category for each block in the system
- Exported as excel file
- If severity categories are defined as system failure modes: number of root contributors per system failure mode
- *Special Functions* ► *Export* ► *Severity Matrix*

## 3. Criticality matrix

- Tabulates the severity category and criticality for each failure mode
- *Special Functions* ► *Export* ► *Criticality Matrix*

Block Name	Block Description	I	II	III	IV	Block and Mode ID	Component Block Description	Failure Mode Description	Severity Category	Criticality
1	POWER SUPPLY	0	0	7	11	1.1.1	CAPACITOR, FIXED CK	Shorted (Electrical)	IV	0.069375
1.1	CAPACITOR, FIXED CK	0	0	1	3	1.1.2	CAPACITOR, FIXED CK	Change of Value	IV	0.0555
1.2	CAPACITOR, FIXED CB	0	0	2	2	1.1.3	CAPACITOR, FIXED CK	Open (Electrical)	III	0.006938
1.3	CAPACITOR, FIXED CK	0	0	2	2	1.1.4	CAPACITOR, FIXED CK	Other	IV	0.006938
1.4	RESISTOR, FIXED RCR	0	0	0	2	1.2.1	CAPACITOR, FIXED CB	Shorted (Electrical)	III	3.40543
1.5	RESISTOR, FIXED RC	0	0	0	2	1.2.2	CAPACITOR, FIXED CB	Open (Electrical)	III	0.729735
1.6	I.C., DIGITAL	0	0	2	0	1.2.3	CAPACITOR, FIXED CB	Change of Value	IV	0.48649
2	CPU BOARD	3	0	3	8	1.2.4	CAPACITOR, FIXED CB	Other	IV	0.243245
2.1	I.C., DIGITAL	0	0	0	1	1.3.1	CAPACITOR, FIXED CK	Shorted (Electrical)	III	0.055985
2.2	CAPACITOR, FIXED CK	2	0	1	1	1.3.2	CAPACITOR, FIXED CK	Change of Value	IV	0.044788

# Fault Tree

## 1. System lifetime

- Unit of system lifetime corresponds to unit of failure
- *Project Options* ► *Calculation*

## 2. Failure and repair models

- 17 model types with different failure and repair characteristics
- Rate models: Constant failure and repair rate
  - Input Rate Model: failure rate  $\lambda$  and repair rate  $\mu$   
 $\mu = 0$ : non-repairable components
  - Input Rate/MTTR: failure rate  $\lambda$  and MTTR  
MTTR = 0: failures are immediately repaired
- Dormant failure model: non repairable components between inspections
  - Three methods: mean (default), max (worst case), IEC 61508
- Local failure model (for one event): Primary Event Properties ► Local Failure Model ► Failure Model Properties
- Generic failure model (for any event): Add ► Failure model ► Failure Model Properties

# Fault Tree

## 3. Calculation methods:

- Cross Product, Esary-Proschan (Bertsche), Rare, Optimum Upper Bound (default), Lower Bound
- *Project Options* ► *Set Generations* ► *Custom Options*

% Difference				
Event Q	Cross Product	Esary-Proschan	Rare	Lower Bound
0.5	0%	4.5%	45%	9.1%
0.1	0%	0.69%	2.5%	0.085%
0.01	0%	0.0096%	0.029%	0.000098%

## 4. Result Summary

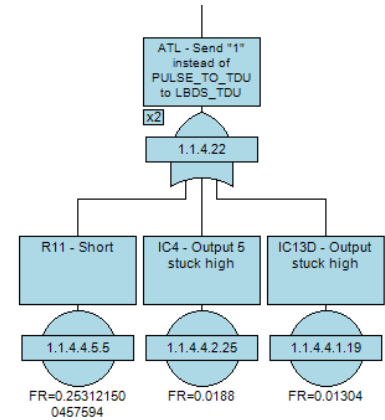
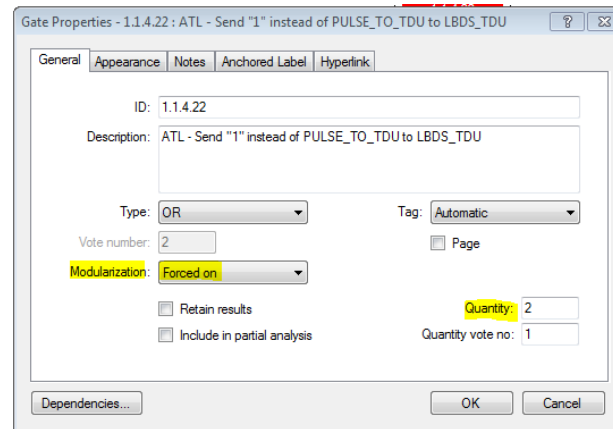
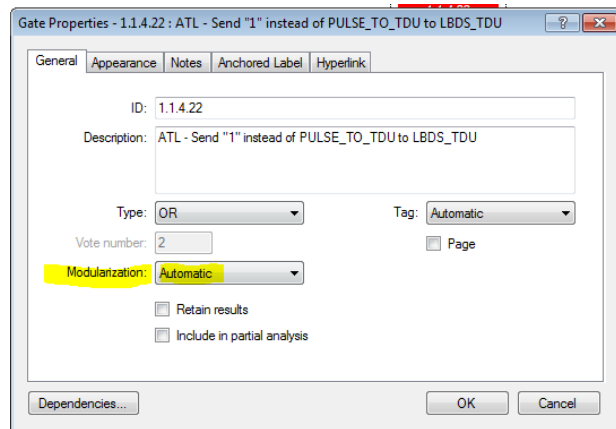
- CFI: Conditional Failure Intensity corresponds to  $\lambda(t)$  (Bertsche):
  - **probability per unit time** that the component or system experiences a failure at time  $t$ , (operating, or was repaired to be as good as new, at time zero and operating at time  $t$ ).
- Unconditional Failure Intensity or Failure Frequency  $\omega(t)$  Frequency:
  - **probability per unit time** that the component or system experiences a failure at time  $t$ , (operating at time zero).
- **CFI- $\lambda(t)$ ,  $\omega(t)$  Difference:** the CFI has an additional condition that the component or system has survived to time  $t$ .



# Fault Tree

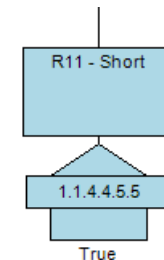
## 5. Quantity of gates

- Specifying a quantity of  $n$  is equivalent to including  $n$  identical gates underneath an gate, with no common cause failures, in the fault tree diagram.
- Quantity values may only be specified for gates that have Modularization set to “Forced on” (default = automatic).



## 6. House event

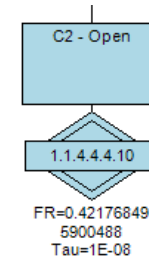
- Used for “what if”: switches branches on ( $Q = 1$ ) and off ( $Q = 0$ )
- *Primary event properties* ▶ *Type* ▶ *House*; *logic mode True or False*



# Fault Tree

## 7. Event symbols dormant

- Option to visualize the failure model
- *Primary event properties* ► *Type* ► *Dormant*



## 8. Append facility

- Alternative to library
- Batch append: transfer all the fault tree structures from a group of projects in one go
- Partial append: append parts of a single project by selecting individual gates
- If branches need to be combined in different fault trees and the event ID needs to remain
- *Special Functions* ► *Append*

## 9. MTTF

- By default not calculated
- Calculation requires numerical integration methods to be employed and may be time consuming for large numbers of minimal cut sets
- *Project Options* ► *Calculation* ► *MTTF/MTBF/MTTR calculations* ► *Method* ► *Standard*

# Fault Tree

## 10. Importance analysis

- Helps determine:
  - Event contribution to TOP event
  - TOP event sensitivity to event changes
  - Weak areas in the system
- 6 different importance measures, most useful (?) Fussell-Vesely Importance (contribution to system Q)

## 11. Confidence analysis

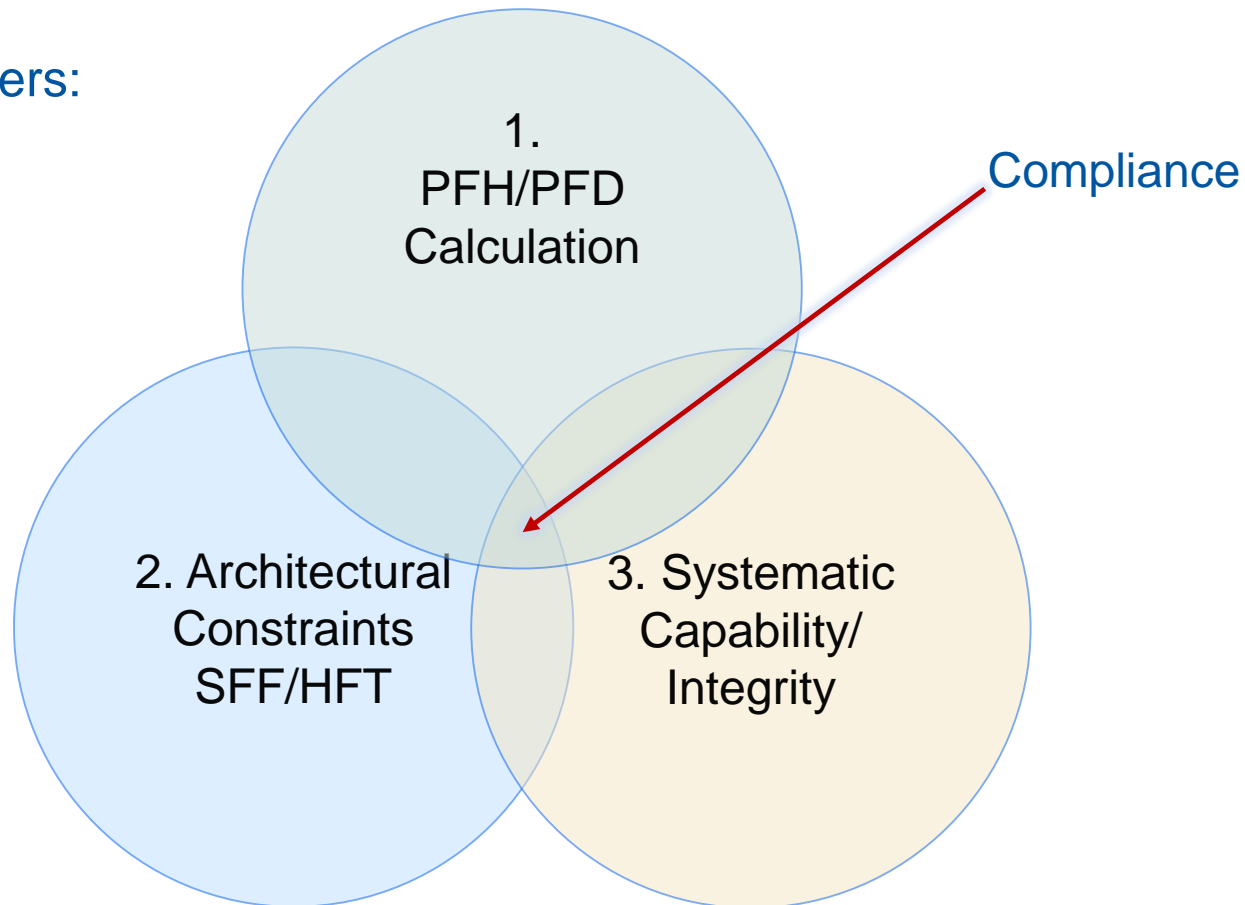
- Introduces uncertainty in component Q
- *Project Options* ► *Confidence*

# 3. Isograph and the IEC 61508 Standard

Saskia Hurst

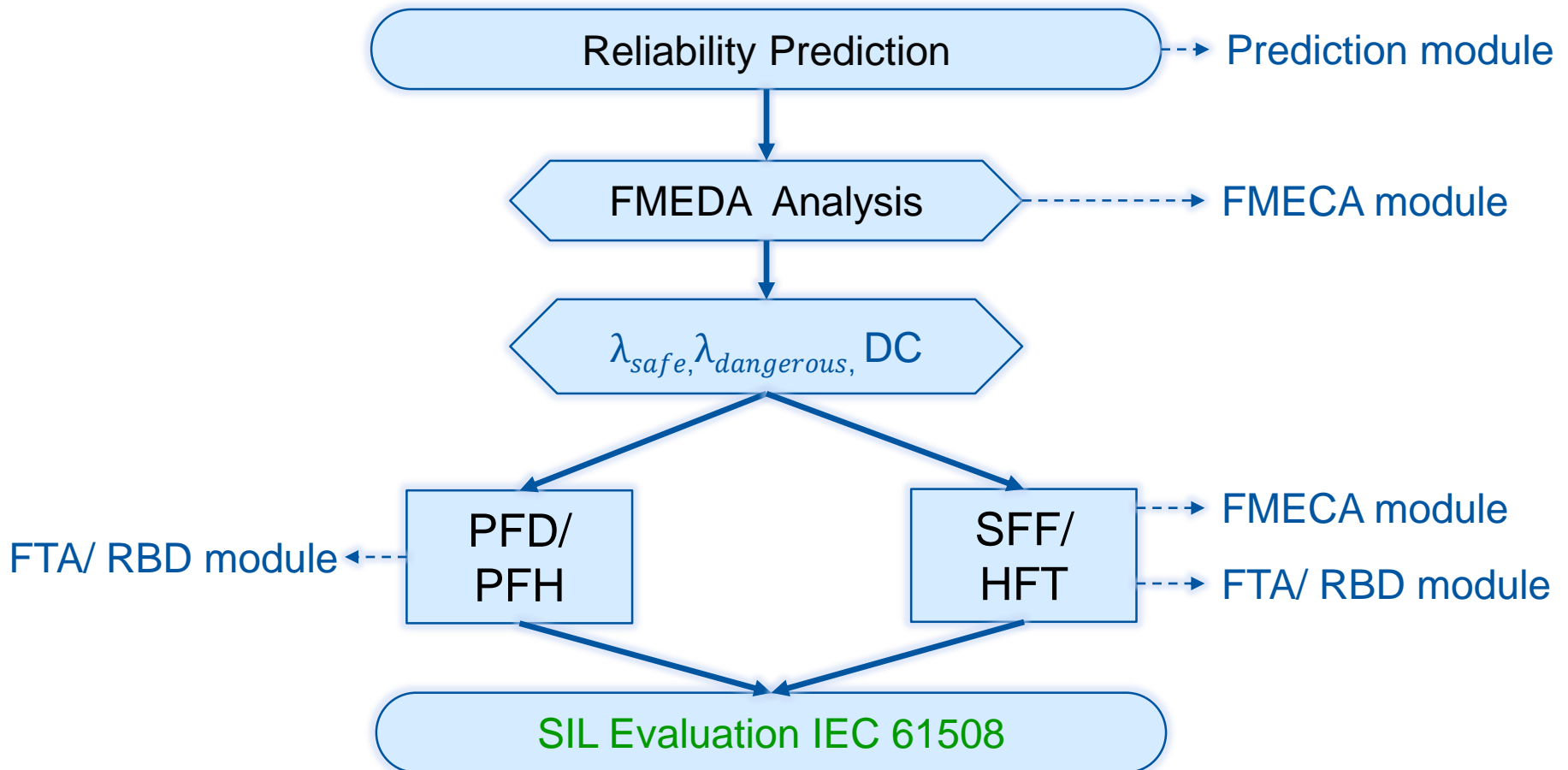
# IEC 61508 - General SIL Verification

Three Barriers:



→ Barrier 1 and barrier 2 can be calculated in Isograph

# IEC 61508 - SIL Quantitative Calculation



# FMEDA (Failure Modes, Effects and Detectability Analysis)

- Takes into account:
  - Failure rates of components,
  - Failure mode probabilities,
  - Failure effect of each failure mode,
  - Diagnostic coverage:

$$SC(\text{Safe Coverage}) = \frac{\lambda_{SD}}{\lambda_{SD} + \lambda_{SU}}; DC(\text{Dangerous Coverage}) = \frac{\lambda_{DD}}{\lambda_{DD} + \lambda_{DU}},$$

- Division into safe  $\lambda_S$  and dangerous  $\lambda_D$  and detectable and undetectable failure rates ( $\lambda_{SD}, \lambda_{SU}, \lambda_{DD}, \lambda_{DU}$ )

ID	Description	Effects defined	Contributors defined	Effects (immediate)	Effects (higher level)	Alpha	Beta	Detectable	Dangerous failure %	Dangerous coverage %	Safe coverage %	Detected safe failure rate	Undetected safe failure rate	Detected dangerous failure rate	Undetected dangerous failure rate	Safe failure fraction
2.1.2.7.1	(CC) C80 - short	Yes	N/A	No 24V	1 No alert CROME 2.1 No measurement	49	1	Yes	100	50	0	0	0	0.000949133	0.000949133	0.5
2.1.2.7.2	(CC) C80 - change in value	Yes	N/A	No effect CB	16 No effect CROME 2.16 No effect CMPU	29	1	No	0	0	0	0	0.00112346	0	0	1
2.1.2.7.3	(CC) C80 - open	Yes	N/A	No effect CB	16 No effect CROME 2.16 No effect CMPU	22	1	No	0	0	0	0	0.000852283	0	0	1

# IEC 61508 - SFF Calculation

- Calculation in the FMECA module of Isograph by doing a FMEDA
- SFF is the ratio of safe and dangerous detected failures to the total failure rate
- Safe Failure Fraction (SFF) for a component:

$$SFF = \frac{\lambda_{SD} + \lambda_{SU} + \lambda_{DD}}{\lambda_{SD} + \lambda_{SU} + \lambda_{DD} + \lambda_{DU}}$$

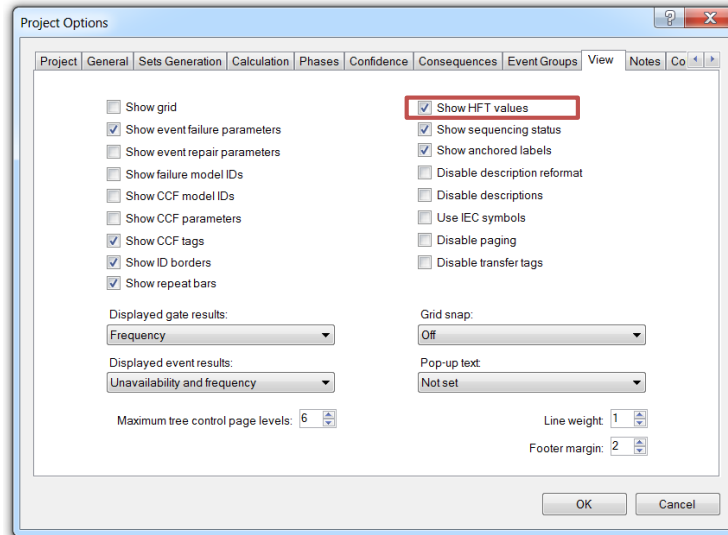
- Safe Failure Fraction (SFF) for a subsystem (safety function):

$$SFF = \frac{\sum \lambda_{SD} + \sum \lambda_{SU} + \sum \lambda_{DD}}{\sum \lambda_{SD} + \sum \lambda_{SU} + \sum \lambda_{DD} + \sum \lambda_{DU}}$$



# IEC 61508 - HFT Calculation

- Calculation in the Fault Tree module of Isograph



- Hardware Fault Tolerance (HFT) is the maximum number of faults that can be tolerated before the loss of the safety function
- i.e.  $HFT = N$  means that  $N + 1$  faults will cause a loss of the function
- Isograph selects HFT by calculating SFF and cross referencing it against the SIL target for the gate (tables 2 and 3 from IEC 61508-2)

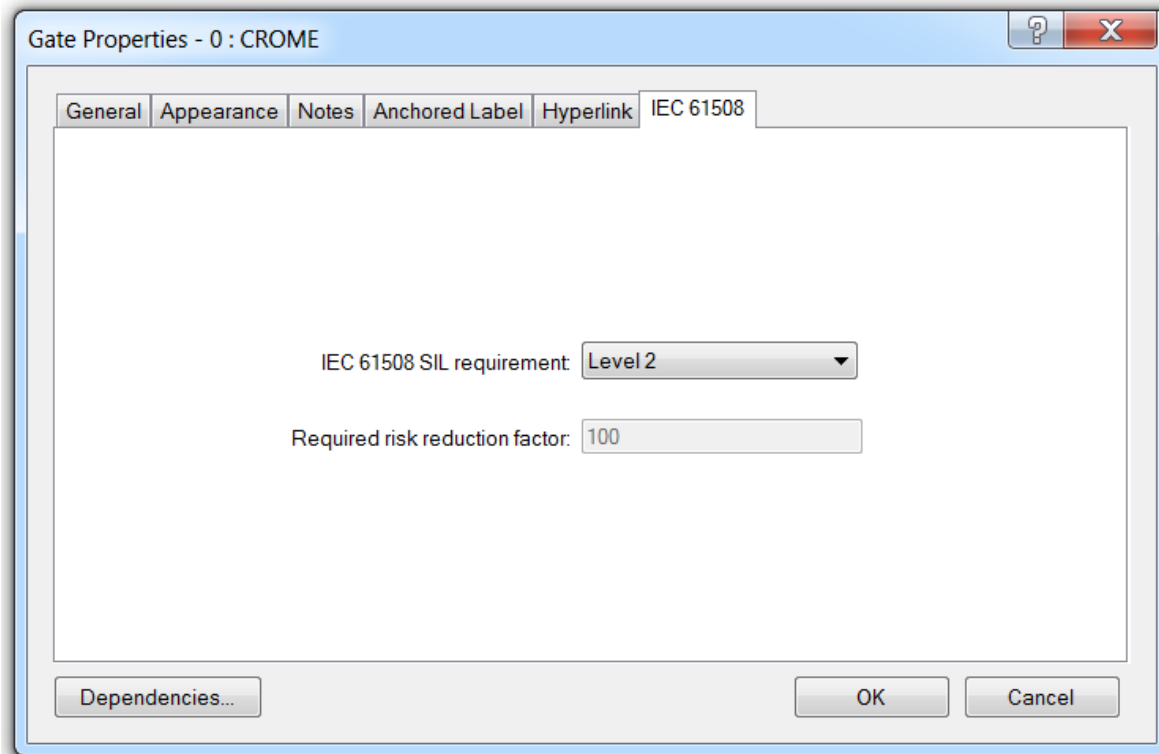
# IEC 61508 - PFH/PFD Calculation

- Calculation in the Fault Tree module or RBD module in Isograph
- Probability of dangerous Failure per Hour PFH (continuous or high demand mode)  
→ Frequency  $\omega$  in Isograph
- Probability of dangerous Failure on Demand PFD (low demand mode)  
→ Unavailability Q in Isograph

Parameter	Point Value
Unavailability	0.00053868
Frequency	0.875807 fpmh
CFI	0.876279 fpmh
Number expected...	8.75807E-07
Unreliability	8.76279E-07

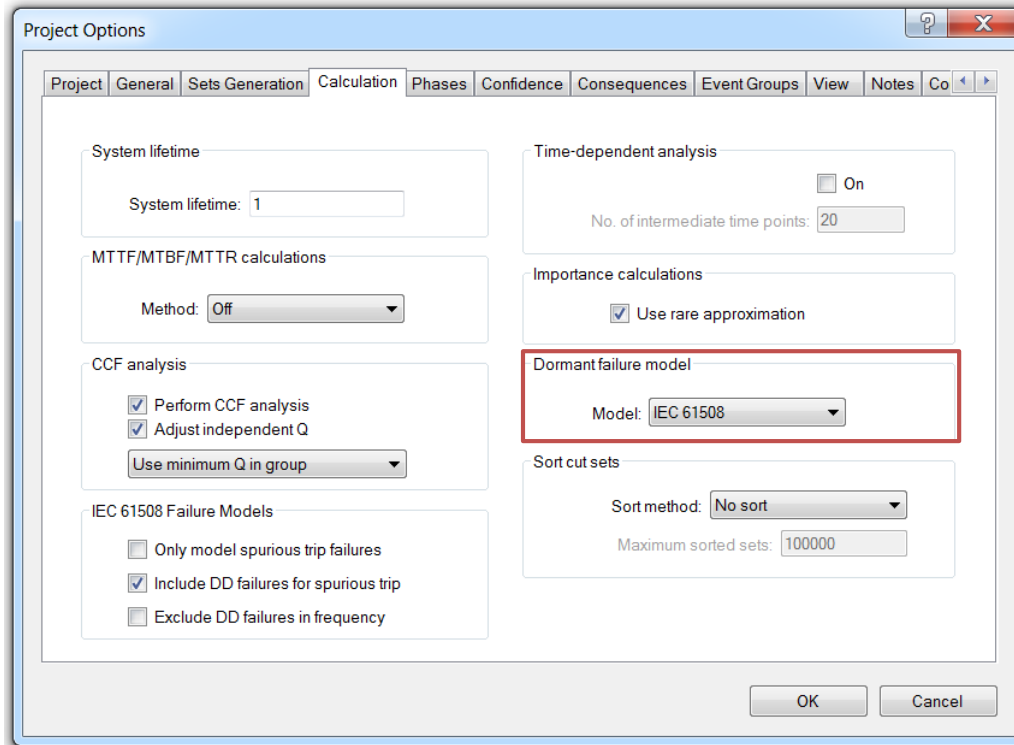
# Important Settings in Isograph

- Set IEC 61508 requirement by either defining
  - Required SIL or
  - Required risk reduction factor



# Important Settings in Isograph

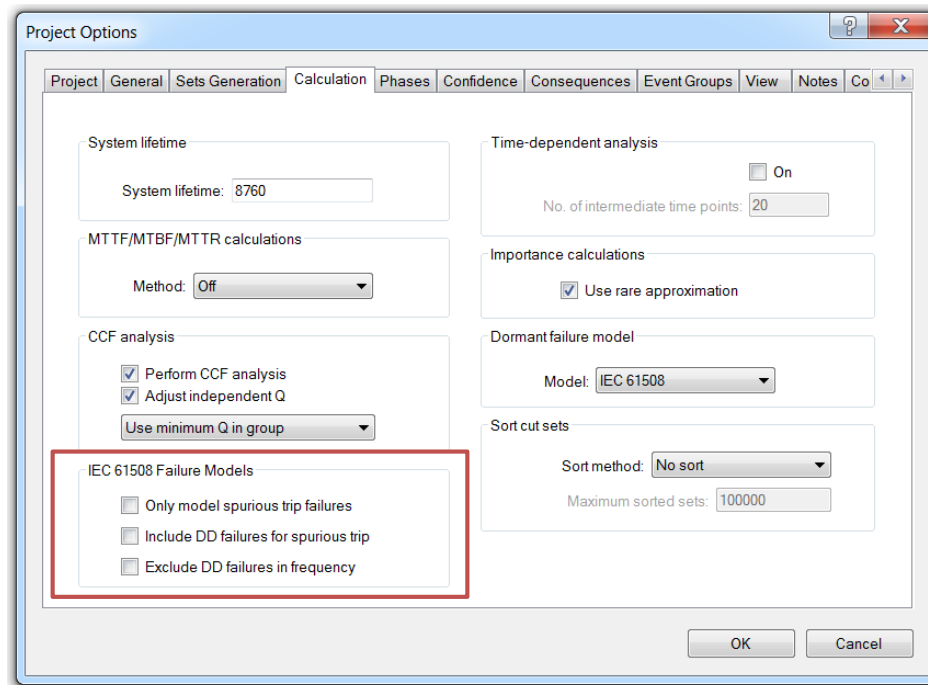
- Dormant failure model → IEC 61508



- Logic for average:
  1. Product of the function (Fault Tree Logic)
  2. Average of the result

# Important Settings in Isograph

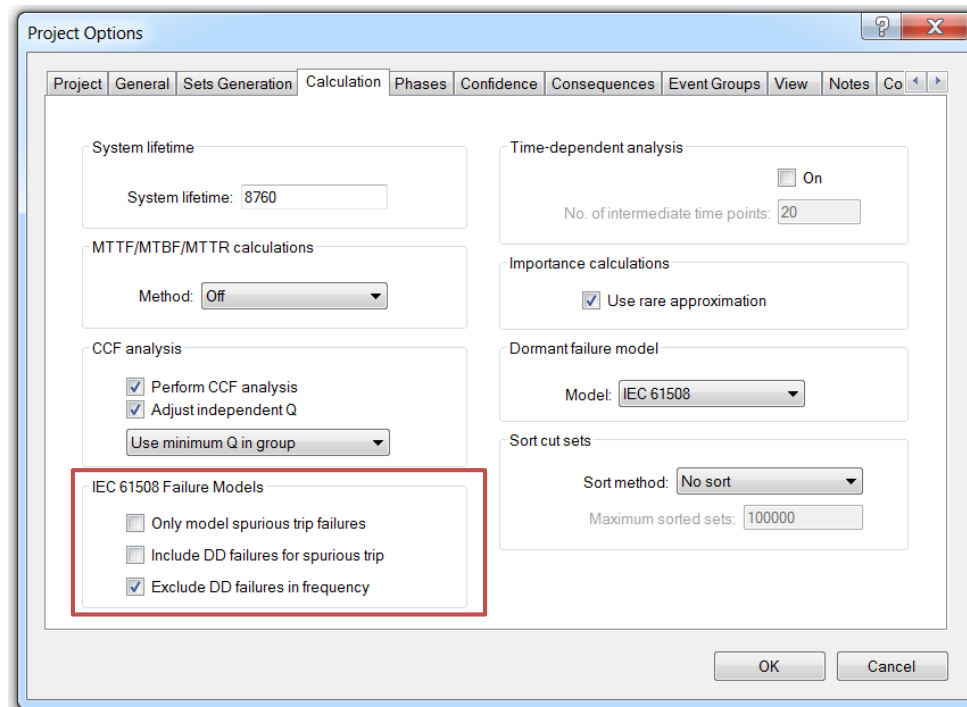
- Default setting: calculation of PFD/PFH with dangerous failure rate  $\lambda_{DU}$



- “Only model spurious trip failure”: calculation of PFH/PFD with  $\lambda_S$
- “Only model spurious trip failure” and “Include DD failures for spurious trip”: calculation of PFH/PFD with  $\lambda_S$  and  $\lambda_{DD}$

# Important Settings in Isograph

- For continuous or high demand functions (PFH): “Exclude DD failures in frequency”



→ Calculation of the frequency (PFH) with only dangerous undetectable failures  $\lambda_{DU}$  according to IEC 61508 standard

# Important Settings in Isograph

- Model type: IEC 61508

Failure Model Properties - IEC : Component 1

General Notes Hyperlink

ID: IEC

Generic data group: Not set

Description: Component 1

Model type: IEC 61508 Type A

Failure rate: 1E-06 per hr

Failure rate Std/Erf: 0 Normal

MTTR: 8 hrs

MTTR Std/Erf: 0 Normal

Test interval: 8760 hrs

Dangerous failure %: 50

Dangerous coverage %: 60

Safe coverage %: 0

Proof test coverage %: 100

Overhaul interval: 10 hrs

Dependencies... Data Link... Inactive OK Cancel

IEC 61508 Parameter Converter

Total failure rate: 1E-06 per hr

Dangerous failure %: 50

Dangerous coverage %: 60

Safe coverage %: 0

Safe failure fraction (%): 80

Dangerous detected failure rate: 3E-07 per hr

Dangerous undetected failure rate: 2E-07 per hr

Safe detected failure rate: 0 per hr

Safe undetected failure rate: 5E-07 per hr

Convert

OK

Cancel

# Common Cause Failures

- $\beta$  Factor Model (used in IEC 61508)

CCF Model Properties - CC1

General | Notes | Hyperlink

ID: CC1

CCF model group: Not set

Description:

CCF model type: Beta

Apply IEC model    IEC settings...

Beta: 0.05

OK    Cancel

IEC 61508=6 CCF Determination - CC1

System & Testing | Separation | Diversity | Complexity | Assessment | Procedures | Competence | Environmental

Subsystem type

Logic subsystem  
 Sensors or final elements

Diagnostic coverage

>= 99%  
 >= 90%  
 >= 60%

Check this box if the equipment under control is put into a safe state before a non-simultaneous common cause failure can effect all the channels. The time taken to assure this safe state should be less than the claimed diagnostic test interval.

Logic subsystem test interval

Less than 1 minute  
 Between 1 and 5 minutes  
 Greater than 5 minutes

Sensors or final elements test interval

Less than 2 hours  
 Between 2 hours and 2 days  
 Between 2 days and 1 week  
 Greater than 1 week

OK    Cancel

- Calculates the proportion of event failures due to common cause

$$Q_1 = (1 - \beta) \cdot Q_T; \quad Q_{CCF} = \beta \cdot Q_T$$

$Q_1$ : Q due to independant failure,     $Q_T$ : Total Q,     $Q_{CCF}$ : Q due to common cause failure

- $\beta$ -factor can be determined by “*Apply IEC model*” with a questionnaire which is implemented in Isograph



